Short Courses and Workshops

JCPDS - International Centre for Diffraction Data

Short Course on Search/Match Methods

The JCPDS-International Centre for Diffraction Data will continue to offer three-day short courses on Search/Match methods at the Swarthmore, PA, headquarters of the International Centre and elsewhere (see attached schedule).

The courses, which are now in their 5th year, are intended to build proficiency of the user in the interpretation of experimental data, especially in the application of the information provided in the *Powder Diffraction File*. The courses should be useful to the novice as well as the experienced powder diffractionist, and all discussions start with the basic principles leading on to useful laboratory procedures. Workbooks are provided to all attendees and these contain a number of experimentally obtained X-ray diffraction data sets which are used as class exercises. During the workbook sessions, the classes are subdivided to match the needs and experience of the attendees.

The course will emphasize the nature and organization of the information in the *Powder Diffraction File* and retrieval and use of this information for interpreting experimentally collected diffraction data. The implications of the accuracy of measurement of d-spacings and intensities of experimental data with respect to use of the powder file will be discussed, as well as common instrumentation and specimen-induced errors. The use of both manual and computer search/match methods for phase identification will be practiced through the use of workbooks. Applications of File data for further characterizing phases will be illustrated using several mineralogical problems and a special X-ray diffraction minerals workbook. Other types of materials may be studied including organic and forensic materials, depending upon the needs of the participants.

Course Schedule

Day 1 Morning: Optimization of data collection

Evaluation of experimental data Instrumental induced errors

Sample induced errors

Day 1 Afternoon: Introduction to the Powder Diffraction File

Role of the JCPDS-ICDD Alphabetic search procedures

The Hanawalt search/match procedure

The Fink search/match procedure

Classical powder diffraction problems

Phase identification

Analysis of polyphase materials
Day 2 Afternoon: Computer techniques in data of

Computer techniques in data collection
Use of the computer in qualitative analysis

Use of CD-ROM based systems

Day 3 Morning: Continuation of problem solving session

Use of the Crystal data file

Other data files (max-d; electron diffraction, etc)

Day 3 Afternoon: General question and answer session

For further information please contact:

Ms. Josephine Felizzi

JCPDS - International Centre for Diffraction Data

1601 Park Lane

Day 2 Morning:

Swarthmore, PA 19081, U.S.A. (215) 328-9403

The cost of a course is \$625.00 which includes textural materials and lunches. Lodging, transportation and other costs are at the expense of the attendee.

JCPDS - International Centre for Diffraction Data Course Schedules

1989

November 14-16 San Jose, CA Hotel Le Baron

1990

February 6-8 Denver, CO April 17-19 Florida

Short Course Announcements

Mineralogical Society of America November 4-5, 1989 Holiday Inn

St. Louis, Missouri

Contact: MSA Business Office, 1625 I Street, N.W. Suite 414, Washington, D.C. 20006. Telephone: (202) 775-4344.

Course to cover some of the more advanced aspects of powder diffraction, beginning with summaries of the techniques. Detailed treatments of quantitative analysis, diffraction applied to clays and glasses, powder diffraction software, and, using mineralogical examples, profile refinement, Rietveld refinement using X-ray data, synchrotron powder diffraction, and neutron diffraction.

Costs: MSA member - \$125 MSA student member - \$25 Non-member - \$165 Student non-member - \$45 British Crystallographic Association February 16-18, 1990

Daresbury

Contact: Dr. John Harding, Room 131, Brunel House, London Road, Derby DE2 8UP, England.

Course to cover powder diffraction methods and use of the Powder Diffraction File. Course limited to 15-20 attendees, registration on first-come, first-served basis.